REVISIONS			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Add vendor CAGE 27014 for device types 01RX and 012X.	1987 MAR 13	M. A. Frye
B	Changed Code Ident. No. to 67268. Added vendor CAGE 01296 as a source of supply. Changes to figure 1, figure 4, and page 11.	1987 NOV 6	M. A. Frye
C	Change vendor CAGE 01295 part number. Delete vendor CAGE 04713. Editorial changes throughout.	1990 OCT 25	M. A. Frye

CURRENT CAGE CODE 67268

REV																								
SHEET																								
REV																								
SHEET																								
REV STATUS OF SHEETS	REV	C	C	C	C	C	C	C	C	C	C	C	C											
	SHEET	1	2	3	4	5	6	7	8	9	10	11	12											

PMIC N/A

STANDARDIZED MILITARY DRAWING

THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE

AMSC N/A

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DRAWING APPROVAL DATE: 12 SEPTEMBER 1986

REVISION LEVEL: C

DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

MICROCIRCUIT, DIGITAL, HIGH SPEED CMOS, 8-BIT MAGNITUDE COMPARATOR, MONOLITHIC SILICON

SIZE	CAGE CODE	
A	14933	5962-86818

SHEET 1

DESC FORM 193-1
SEP 87

* U.S. GOVERNMENT PRINTING OFFICE: 1987 — 748-129/60912

5962-E1765

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part or Identifying Number (PIN). The PIN shall be as shown in the following example:

5962-86818	01	R	X
Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510

1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	54HC688	8-bit magnitude comparator, (equality detector)

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
R	D-8 (20-lead, 1.060" x .310" x .200"), dual-in-line package
2	C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package

1.3 Absolute maximum ratings. 1/

Supply voltage range	-0.5 V dc to +7.0 V dc
DC input voltage	-0.5 V dc to V_{CC} + 0.5 V dc
DC output voltage	-0.5 V dc to V_{CC} + 0.5 V dc
Clamp diode current	±20 mA
DC output current (per pin)	±25 mA
DC V_{CC} or GND current (per pin)	±50 mA
Storage temperature range	-65°C to +150°C
Maximum power dissipation (P_D) 2/	500 mW
Lead temperature (soldering, 10 seconds)	+260°C
Thermal resistance, junction-to-case (θ_{JC})	See MIL-M-38510, appendix C
Junction temperature (T_J)	+175°C

1/ Unless otherwise specified, all voltages are referenced to ground.

2/ For T_C = +100°C to +125°C, derate linearly at 12 mW/°C.

1.4 Recommended operating conditions.

Supply voltage (V_{CC})	+2.0 V dc to +6.0 V dc
Case operating temperature range (T_C)	-55°C to +125°C
Input voltage range ($-V_{IN}$)	0.0 V to V_{CC}
Output voltage range ($-V_{OUT}$)	0.0 V to V_{CC}
Input rise or fall time:	
V_{CC} = 2.0 V	0 to 1000 ns
V_{CC} = 4.5 V	0 to 500 ns
V_{CC} = 6.0 V	0 to 400 ns

2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions $-55°C < T_C < +125°C$ 1/ unless otherwise specified		Group A subgroups	Limits		Unit
					Min	Max	
High level output voltage	V_{OH}	$V_{IN} = V_{IH}$ minimum or V_{IL} maximum $\lvert I_O \rvert = 20\ \mu A$	$V_{CC} = 2.0$ V	1,2,3	1.9		V
			$V_{CC} = 4.5$ V		4.4		
			$V_{CC} = 6.0$ V		5.9		
		$\lvert I_O \rvert = 4.0$ mA $V_{IN} = V_{IH}$ minimum or V_{IL} maximum	$V_{CC} = 4.5$ V		3.7		
		$\lvert I_O \rvert = 5.2$ mA $V_{IN} = V_{IH}$ minimum or V_{IL} maximum	$V_{CC} = 6.0$ V		5.2		
Low level output voltage	V_{OL}	$V_{IN} = V_{IH}$ minimum or V_{IL} maximum $\lvert I_O \rvert = 20\ \mu A$	$V_{CC} = 2.0$ V	1,2,3		0.1	V
			$V_{CC} = 4.5$ V			0.1	
			$V_{CC} = 6.0$ V			0.1	
		$\lvert I_O \rvert = 4.0$ mA $V_{IN} = V_{IH}$ minimum or V_{IL} maximum	$V_{CC} = 4.5$ V			0.4	
		$\lvert I_O \rvert = 5.2$ mA $V_{IN} = V_{IH}$ minimum or V_{IL} maximum	$V_{CC} = 6.0$ V			0.4	
High level input voltage	V_{IH}	2/	$V_{CC} = 2.0$ V	1,2,3	1.5		V
			$V_{CC} = 4.5$ V		3.15		
			$V_{CC} = 6.0$ V		4.2		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions $-55°C < T_C < +125°C$ 1/ unless otherwise specified		Group A subgroups	Limits Min	Limits Max	Unit
Low level input voltage	V_{IL}	2/	V_{CC} = 2.0 V	1,2,3		0.3	V
			V_{CC} = 4.5 V			0.9	
			V_{CC} = 6.0 V			1.2	
Input capacitance	C_{IN}	V_{CC} = GND, See 4.3.1c		4		10	pF
Quiescent current	I_{CC}	V_{CC} = 6.0 V, V_{IN} = V_{CC} or GND		1,2,3		160	µA
Input leakage current	I_{IN}	V_{CC} = 6.0 V, V_{IN} = V_{CC} or GND		1,2,3		±1.0	µA
Functional tests		See 4.3.1d		7,8			
Propagation delay, input A or B to output A = B 3/	t_{PHL1}, t_{PLH1}	T_C = +25°C, C_L = 50 pF, See figure 4	V_{CC} = 2.0 V	9		210	ns
			V_{CC} = 4.5 V			42	
			V_{CC} = 6.0 V			36	
		T_C = -55°C, +125°C, C_L = 50 pF, See figure 4	V_{CC} = 2.0 V	10,11		315	ns
			V_{CC} = 4.5 V			63	
			V_{CC} = 6.0 V			54	

See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions $-55°C \le T_C \le +125°C$ 1/ unless otherwise specified		Group A subgroups	Limits Min	Limits Max	Unit
Propagation delay, cascade input to output A = B 3/	t_{PHL2}, t_{PLH2}	T_C = +25°C, C_L = 50 pF, See figure 4	V_{CC} = 2.0 V	9		120	ns
			V_{CC} = 4.5 V			24	
			V_{CC} = 6.0 V			20	
		T_C = -55°C, +125°C C_L = 50 pF, See figure 4	V_{CC} = 2.0 V	10,11		180	ns
			V_{CC} = 4.5 V			35	
			V_{CC} = 6.0 V			31	
Transition time 4/	t_{TLH}, t_{THL}	T_C = +25°C, C_L = 50 pF, See figure 4	V_{CC} = 2.0 V	9		75	ns
			V_{CC} = 4.5 V			15	
			V_{CC} = 6.0 V			13	
		T_C = -55°C, +125°C C_L = 50 pF See figure 4	V_{CC} = 2.0 V	10,11		110	ns
			V_{CC} = 4.5 V			22	
			V_{CC} = 6.0 V			19	

1/ For a power supply of 5 V ±10 percent, the worst case output voltage (V_{OH} and V_{OL}) occur for HC at 4.5 V. Thus, the 4.5 V values should be used when designing with this supply. Worst case V_{IH} and V_{IL} occur at V_{CC} = 5.5 V and 4.5 V, respectively. (The V_{IH} value at 5.5 V is 3.85 V.) The worst case leakage current (I_{IN}, I_{CC}, and I_{OZ}) occur for CMOS at the higher voltage and so the 6.0 V values should be used. Power dissipation capacitance (CPD), typically 45 pF, determines the no load dynamic power consumption, P_D = CPD V_{CC2} f + I_{CC} V_{CC}, and the no load dynamic current consumption, IS = CPD V_{CC} f + I_{CC}.

2/ V_{IH} and V_{IL} tests are not required if applied as forcing functions for V_{OH} and V_{OL}.

3/ AC testing at V_{CC} = 2.0 V and V_{CC} = 6.0 V shall be guaranteed, if not tested, to the specified limits in table I.

4/ Transition time (t_{TLH} and t_{THL}), if not tested, shall be guaranteed to the specified limits in table I.

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Device type	01
Case outline	R and 2
Terminal number	Terminal symbol
1	CASCADE INPUT
2	A0
3	B0
4	A1
5	B1
6	A2
7	B2
8	A3
9	B3
10	GND
11	A4
12	B4
13	A5
14	B5
15	A6
16	B6
17	A7
18	B7
19	A=B
20	V_{CC}

FIGURE 1. Terminal connections.

Inputs		Output
An, Bn	Cascade input	A=B
A=B	L	L
A>B	L	H
A<B	L	H
X	H	H

L = Low logic level
H = High level logic

FIGURE 2. Truth table.

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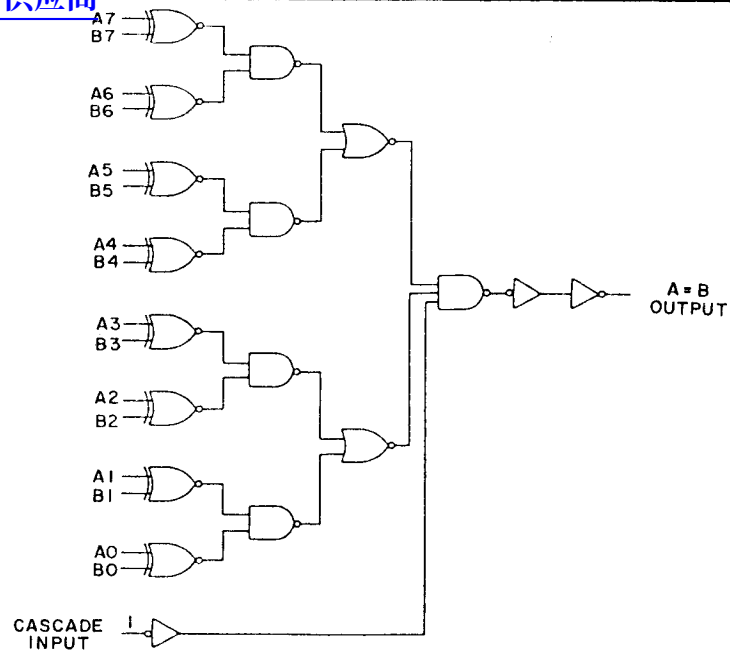
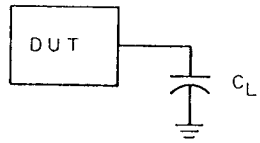


FIGURE 3. Logic diagram.



C_L = 50 pF, INCLUDES PROBE AND JIG CAPACITANCE

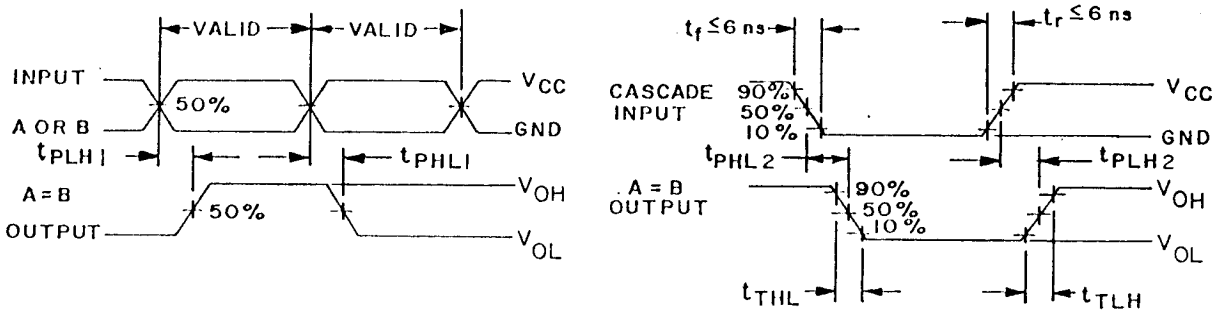


FIGURE 4. Switching waveform and test circuit.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A or B or C or D using the circuit submitted with the certificate of compliance (see 3.6 herein)

(2) T_A = +125°C, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*,2,3,9
Group A test requirements (method 5005)	1,2,3,4,8,9, 10,11
Groups C and D end-point electrical parameters (method 5005)	1,2,3
Additional electrical subgroups for group C periodic inspections	---

* PDA applies to subgroup 1.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroup 4 (C_{IN} measurement) shall be measured only for the initial test and after process or design changes which may affect capacitance. Capacitance shall be measured between the designated terminal and GND at a frequency of 1 MHz. Test all applicable pins of five devices with zero failures.

d. Subgroup 7 and 8 tests shall include verification of the truth table.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883.

(1) Test condition A or B or C or D using the circuit submitted with the certificate of compliance (see 3.6 herein).

(2) T_A = +125°C, minimum.

(3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Replaceability is determined as follows: When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as PIN M38510/66105.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. The coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECS, telephone 513-296-6022.

6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS.